WEST Search History

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DATE: Wednesday, September 27, 2006

Hide?	**Set Name**	**Query**	**Hit Count**
		DB=PGPB; PLUR=YES; OP=OR	
☐	L28	("scan chain" with yield with (fail or probabilit$) with statistic$)[clm]	0
☐	L27	(placement and (routing or wiring) with "test data")[clm]	0
☐	L26	"global placement and wiring program"[clm]	0
☐	L25	"global placment and wiring program"[clm]	0
☐	L24	L23 and (sensitivit$ or dominant)[clm]	1
☐	L23	(model with "scan chain")[clm]	8
☐	L22	L19 and "scan chain"[clm]	3
☐	L21	L20 and "scan chain"[clm]	1
☐	L20	L19 and latch$[clm]	65
☐	L19	("process variation" or integrity)[clm]	4549
☐	L18	(correlat$ with "scan chain" with process)[clm]	1
☐	L17	(correlat$ with "scan chain" with failure)[clm]	1
☐	L16	(cluster$ with "scan chain" with failure)[clm]	1
☐	L15	L14 and (restrict$ with layer)[clm]	1
☐	L14	(constrain$ with "scan chain")[clm]	10
☐	L13	(bias$ with "scan chain" with routing)[clm]	1
☐	L12	l11 and (maximi$ with uniformity)[clm]	1
☐	L11	"scan chain"[clm] with latch$[clm]	58
☐	L10	l8 and L9	2
☐	L9	l7 and layer[clm]	73
☐	L8	L7 and latch$[clm]	4
☐	L7	(sensitivities with (fabrication or process))[clm]	315
☐	L6	(associat$ with parameter with "scan chain")[clm]	1
☐	L5	(physical near5 "scan chain")[clm]	3
☐	L4	l1 and model[clm]	24
☐	L3	l1 and L2	2
☐	L2	(database with (fabrication or process))[clm]	3422
☐	L1	"scan chain"[clm]	417

END OF SEARCH HISTORY